

<b>Notice of References Cited</b>	Application/Control No. 10/519,650		Applicant(s)/Patent Under Reexamination FRENCH ET AL.	
	Examiner David Goodwin		Art Unit 2818	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,045,954	04-2000	Dai et al.	430/5
*	B	US-6,387,573	05-2002	Park et al.	430/5
*	C	US-2005/0089763	04-2005	Tan et al.	430/005
*	D	US-2005/0140986	06-2005	Butler, Hans	356/509
*	E	US-2006/0027809	02-2006	Ogawa et al.	257/066
*	F	US-5,882,827	03-1999	Nakao, Shuji	430/5
*	G	US-7,008,735	03-2006	Yang, Chih-Cheng	430/5
*	H	US-2001/0009745	07-2001	Kim, Hyoung-joon	430/5
*	I	US-2002/0031725	03-2002	Sugita et al.	430/311
*	J	US-2002/0061452	05-2002	Nozawa et al.	430/5
*	K	US-2005/0170290	08-2005	Dejima, Yoshio	430/312
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.